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Attorney's Docket No. 07977-279001

Application No. 09/892,225

**Information Disclosure Statement** 

by Applicant (Use several sheets if necessary) Shunpei Yamazaki, et al.

Filing Date

Group Art Unit 1722

(37 CFR §1.98(b))

June 25, 2001

Applicant

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		closure Statement	Applicant Shunpei Yamazaki, et al.		
	(Use several sheets if necessary)		Filing Date	Group Art Unit	
	(37 CFR §1.98(b))		June 25, 2001	1722	

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